

January 2008

QRD1113, QRD1114 Reflective Object Sensor

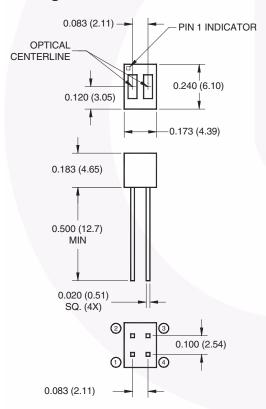
Features

- Phototransistor Output
- No contact surface sensing
- Unfocused for sensing diffused surfaces
- Compact Package
- Daylight filter on sensor

Description

The QRD1113/14 reflective sensor consists of an infrared emitting diode and an NPN silicon phototransistor mounted side by side in a black plastic housing. The onaxis radiation of the emitter and the on-axis response of the detector are both perpendicular to the face of the QRD1113/14. The phototransistor responds to radiation emitted from the diode only when a reflective object or surface is in the field of view of the detector.

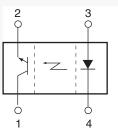
Package Dimensions



PIN 1 COLLECTOR PIN 3 ANODE
PIN 2 EMITTER PIN 4 CATHODE



Schematic



Notes:

- 1. Dimensions for all drawings are in inches (millimeters).
- 2. Tolerance of ± .010 (.25) on all non-nominal dimensions unless otherwise specified.
- 3. Pins 2 and 4 typically .050" shorter than pins 1 and 3.
- 4. Dimensions controlled at housing surface.

Absolute Maximum Ratings (T_A = 25°C unless otherwise specified)

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Rating	Units	
T _{OPR}	Operating Temperature	-40 to +85	°C	
T _{STG}	Storage Temperature	-40 to +100	°C	
T _{SOL-I}	Lead Temperature (Solder Iron) ^(2,3)	240 for 5 sec	°C	
T _{SOL-F}	Lead Temperature (Solder Flow) ^(2,3) 260 for 10 sec			
EMITTER				
I _F	Continuous Forward Current	50	mA	
V _R	Reverse Voltage	5	V	
P _D	Power Dissipation ⁽¹⁾	100	mW	
SENSOR				
V _{CEO}	Collector-Emitter Voltage	30	V	
V _{ECO}	Emitter-Collector Voltage		V	
P _D	Power Dissipation ⁽¹⁾	100	mW	

Electrical/Optical Characteristics (T_A = 25°C)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units	
INPUT (Er	INPUT (Emitter)						
V _F	Forward Voltage	I _F = 20mA			1.7	V	
I _R	Reverse Leakage Current	$V_R = 5V$			100	μA	
λ _{PE}	Peak Emission Wavelength	I _F = 20mA		940		nm	
OUTPUT (OUTPUT (Sensor)						
BV _{CEO}	Collector-Emitter Breakdown	I _C = 1mA	30			V	
BV _{ECO}	Emitter-Collector Breakdown	I _E = 0.1mA	5			V	
I _D	Dark Current	V _{CE} = 10 V, I _F = 0mA			100	nA	
COUPLED							
I _{C(ON)}	QRD1113 Collector Current	I _F = 20mA, V _{CE} = 5V, D = .050"(6,8)	0.300			mA	
I _{C(ON)}	QRD1114 Collector Current	I _F = 20mA, V _{CE} = 5V, D = .050"(6,8)	1			mA	
V _{CE(SAT)}	Collector Emitter Saturation Voltage	$I_F = 40 \text{mA}, I_C = 100 \mu\text{A}, D = .050^{\text{"}(6,8)}$			0.4	V	
I _{CX}	Cross Talk	$I_F = 20 \text{mA}, V_{CE} = 5 \text{V}, E_E = 0^{(7)}$.200	10	μΑ	
t _r	Rise Time	$V_{CE} = 5V, R_{L} = 100\Omega, I_{C(ON)} = 5mA$		10		μs	
t _f	Fall Time			50		μs	

Notes:

- 1. Derate power dissipation linearly 1.33mW/°C above 25°C.
- 2. RMA flux is recommended.
- 3. Methanol or isopropyl alcohols are recommended as cleaning agents.
- 4. Soldering iron tip 1/16" (1.6 mm) minimum from housing.
- 5. As long as leads are not under any stress or spring tension.
- 6. D is the distance from the sensor face to the reflective surface.
- 7. Crosstalk (I_{CK}) is the collector current measured with the indicated current on the input diode and with no reflective surface.
- 8. Measured using Eastman Kodak neutral white test card with 90% diffused reflecting as a reflecting surface.

Typical Performance Curves

Fig. 1 Forward Voltage vs. Forward Current

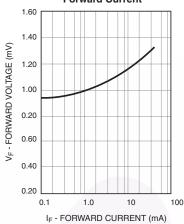


Fig. 2 Normalized Collector Current vs.
Forward Current

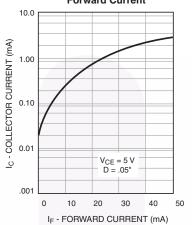


Fig. 3 Normalized Collector Current vs. Temperature

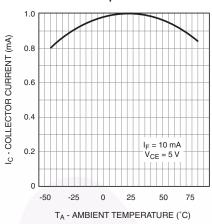


Fig. 4 Normalized Collector Dark Current vs.
Temperature

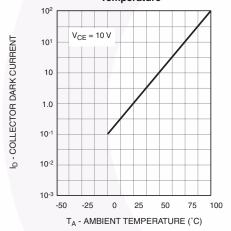


Fig. 5 Normalized Collector Current vs. Distance NORMALIZED - COLLECTOR CURRENT (mA) 1.0 .9 I_F = 20 mA V_{CE} = 5 V .8 .7 .6 .5 .4 .3 .2 200 450 250 300 500

REFLECTIVE SURFACE DISTANCE (mils)





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